



# M&M 2013

## MICROSCOPY & MICROANALYSIS

August 4 - 8 • Indianapolis, IN



Official M&M  
**Exhibition and Meeting Guide**

# Innovative History Driving the Future of Discovery



Test-drive the Ultimate SEM at M&M 2013.....

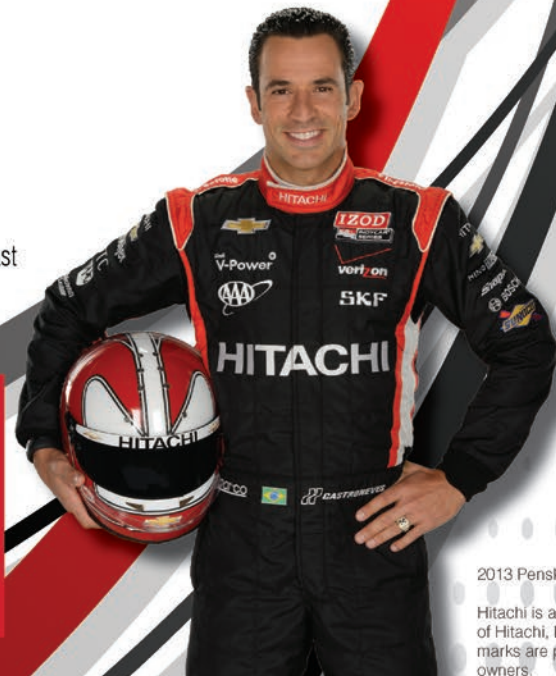
*Hitachi's next generation Cold Field Emission SEM offers unmatched low-voltage imaging and comprehensive analytical microanalysis with the uncompromised performance of CFE.*

New CFE Technology from Hitachi:

- Increased probe current for S/N and analytical performance
- Unparalleled imaging throughput with improved CFE beam stability
- Enhanced deceleration and energy filtering system affording fine contrast differentiation at low accelerating voltages

**Meet Helio Castroneves, three time Indy 500® Champion and driver of the #3 Hitachi Team Penske Chevy Dallara, at the Hitachi Booth #1304 on Tuesday, August 6th. Enter to win an autographed #3 Hitachi diecast model car.**

Hitachi is an official sponsor of Penske Racing.



2013 Penske Racing, Inc.

Hitachi is a registered trademark of Hitachi, Ltd. All other trademarks are property of respective owners.

Hitachi High Technologies America, Inc.  
toll free: 800-548-9001 (US & Canada)  
email: emdwebsite@hitachi-hita.com  
www.hitachi-hita.com

M&M 2013 Booth #1304

**HITACHI**  
Inspire the Next

Copyright © 2013 Hitachi High Technologies America, Inc. All rights reserved.  
<https://doi.org/10.1002/9781118478111.ch047> Published online by Cambridge University Press

# Microscopy & Microanalysis

The Official M&M 2013 Exhibition and Meeting Guide  
Indianapolis, Indiana, USA • August 4–8, 2013



---

## Table of Contents

Welcome from the Society Presidents	2
Society Sustaining Members	4
M&M 2013 Sponsors	6
Essential Meeting Information	8
General Meeting and Information	10
Indiana Convention Center	12
Meeting and Events	14
Convention Center Map	16
MSA MegaBooth	18
Company Listing	20
Product Categories	36
Index to Advertisers	46
Exhibitors' List	48
Exhibit Hall Map	Back cover foldout